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FACULTY OF ENGINEERING AND  
TECHNOLOGY

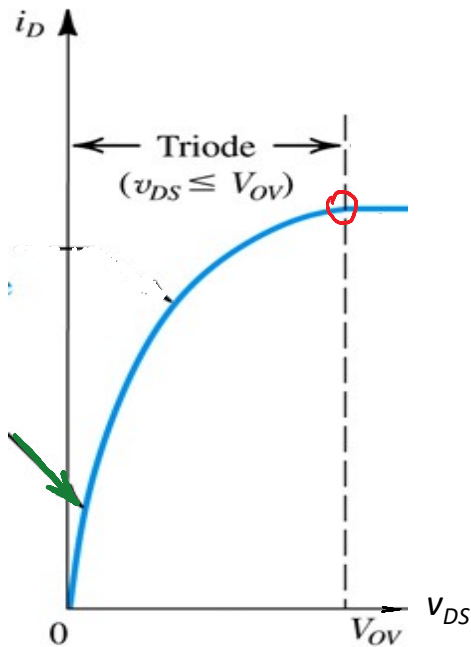
MEC-022

Lecture - 07

## N-MOSFET: Triode Region Characteristics

- The expression for  $i_D$  is quadratic in  $v_{DS}$  with max reached at  $v_{DS} = v_{GS} - v_{TN} = v_{OV}$
- For small  $v_{DS} \ll v_{GS} - v_{TN}$ , the characteristics  $i_D$  vs.  $v_{DS}$  appear to be linear (triode region, linear)

$$i_D = K_n \left( v_{GS} - V_{TN} - \frac{v_{DS}}{2} \right) v_{DS}$$

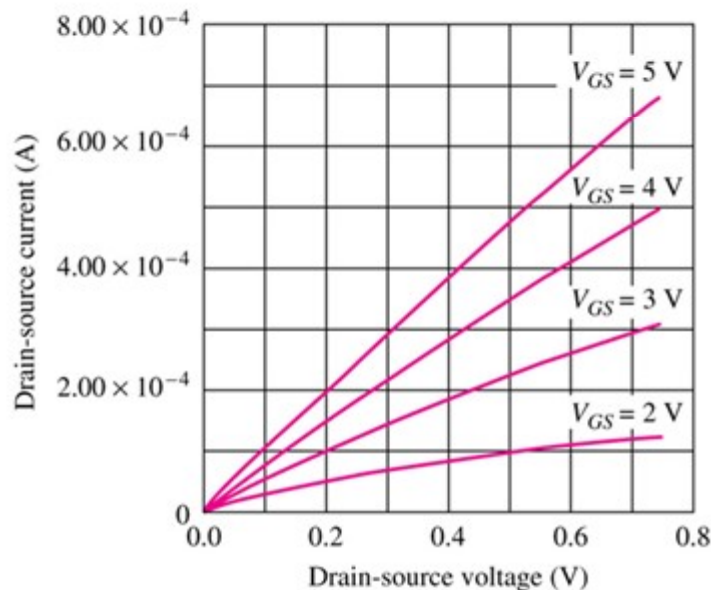


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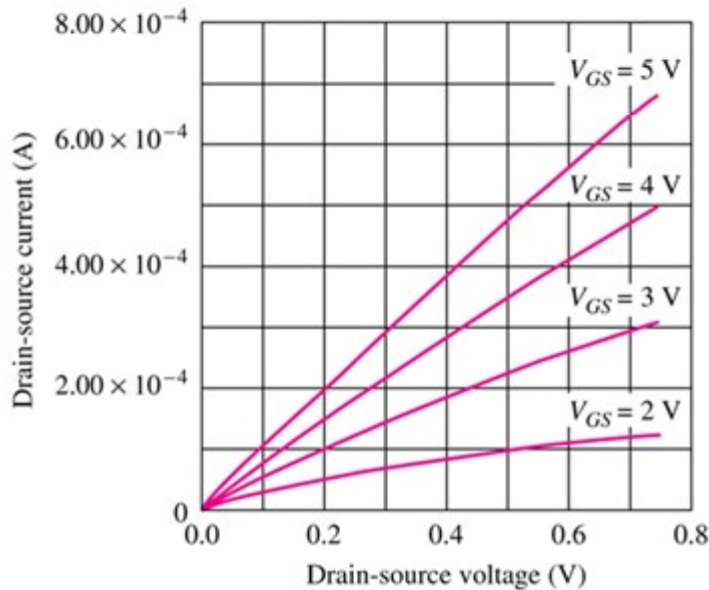
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where **on-resistance**:

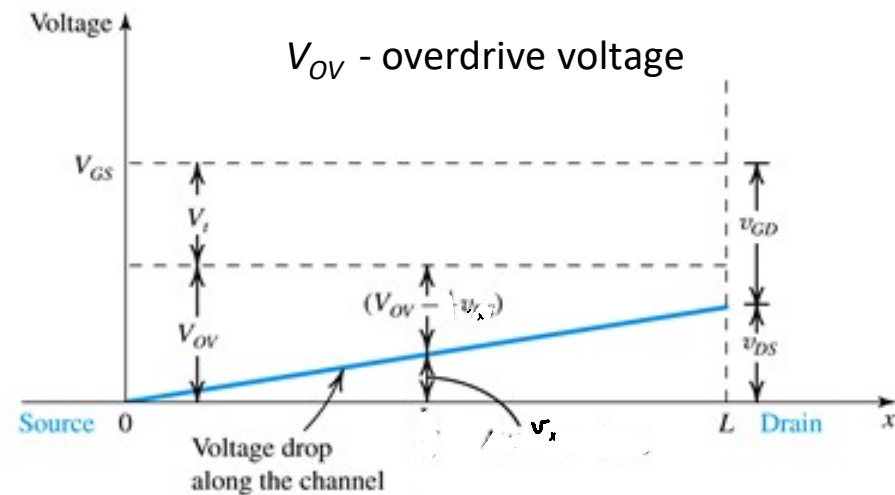
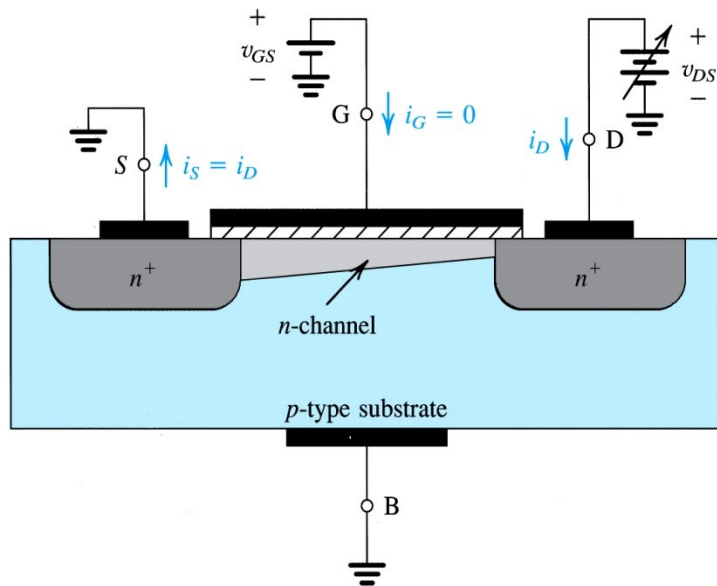
$$R_{on} = \frac{1}{K_n \frac{W}{L} (V_{GS} - V_{TN} - V_{DS})} \Big|_{v_{DS} \rightarrow 0}$$

$$= \frac{1}{K_n \frac{W}{L} (V_{GS} - V_{TN})} = R_{on}(V_{GS})$$



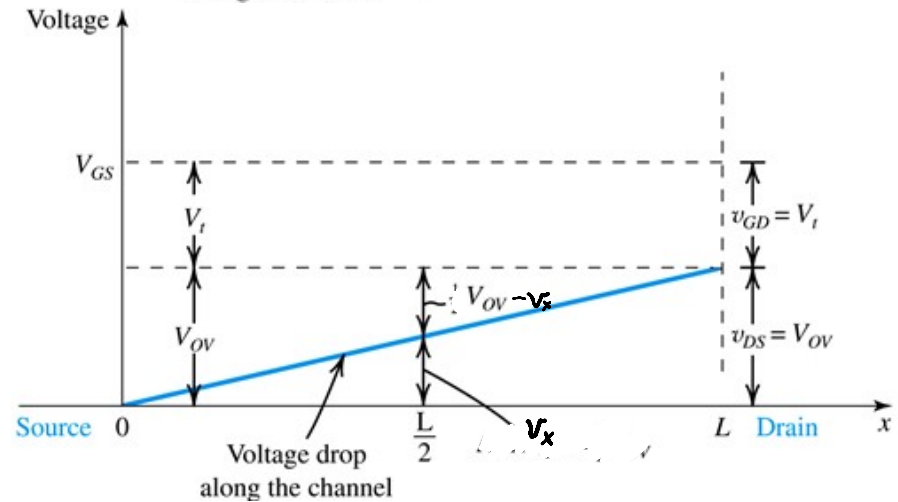
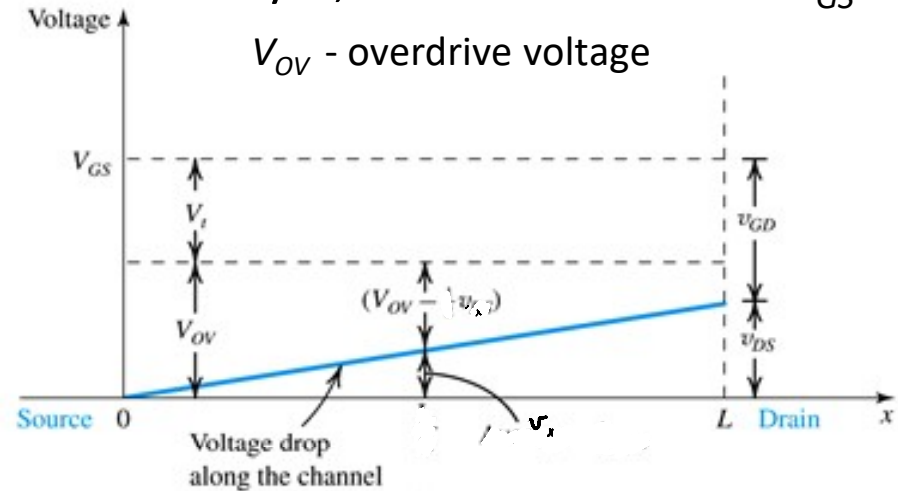
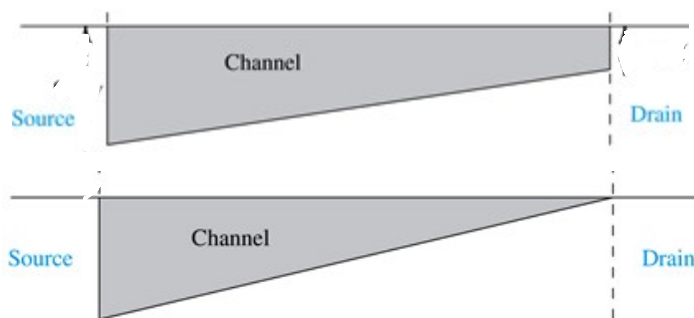
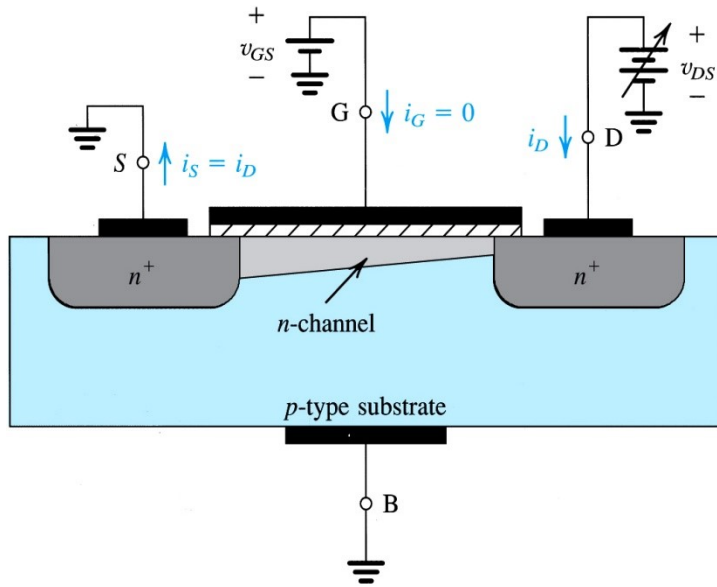
# NMOS Transistor: inversion layer change

If we increase  $v_{DS}$ , and it's no more  $v_{DS} \ll V_{GS} - V_{TN} = V_{OV}$  (triode region limit), it starts influencing the depth of induced inversion layer, for which we need  $V_{GS} > V_{TN}$ .



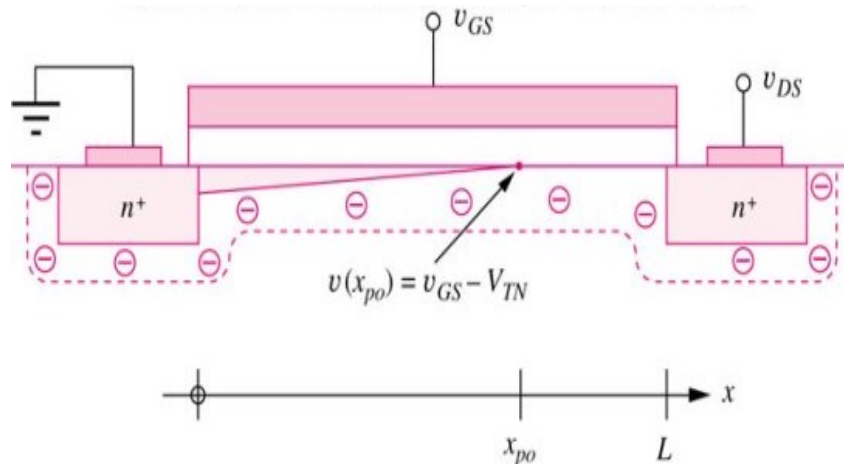
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$v_{DS} = V_{OV}$  - pinch-off voltage, saturation region begins

## NMOS Transistor: Saturation Region

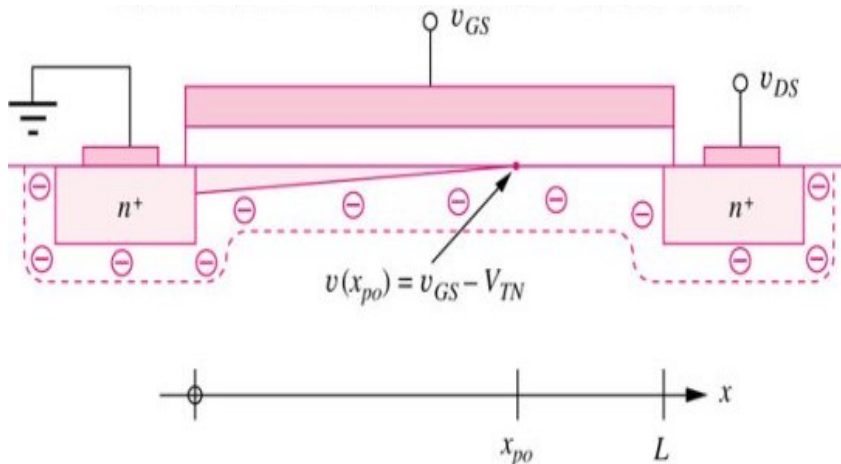


What is the current in saturation region?

- When  $v_{DS}$  increases above triode region limit, channel region almost disappears, MOSFET also said to be pinched-off.
- Current saturates at (almost) constant value, independent of  $v_{DS}$ .

$v_{DSAT} = v_{GS} - V_{TN}$  is also called **saturation or pinch-off voltage**.

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Substituting  $v_{DS} = v_{GS} - V_{TN}$  into previous equation for drain current, we get

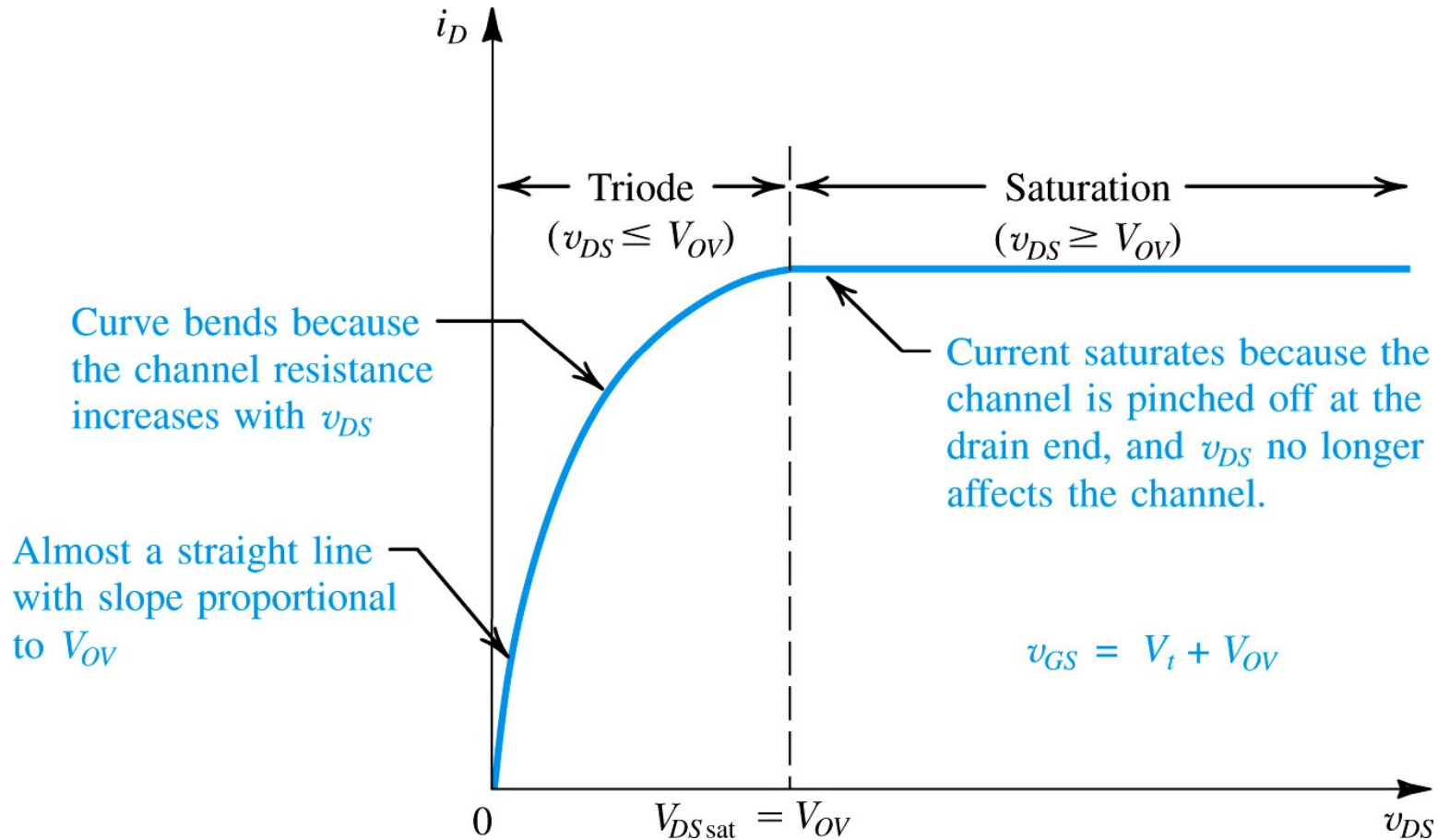
$$i_D = \frac{K'_n W}{2 L} (v_{GS} - V_{TN})^2$$

$$\text{for } v_{DS} \geq v_{GS} - V_{TN}$$

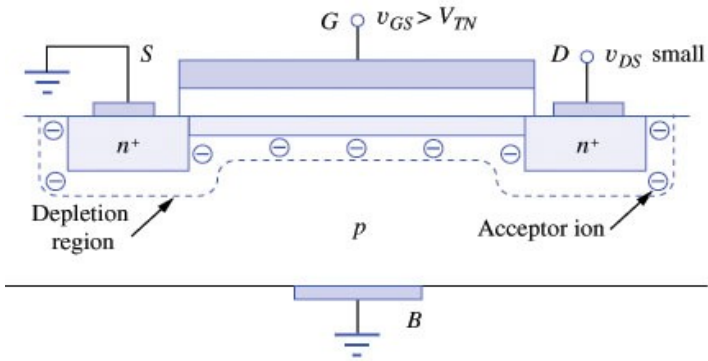
- Saturation region operation mostly used for analog amplification.



# NMOS Transistor: $i_D$ -characteristic

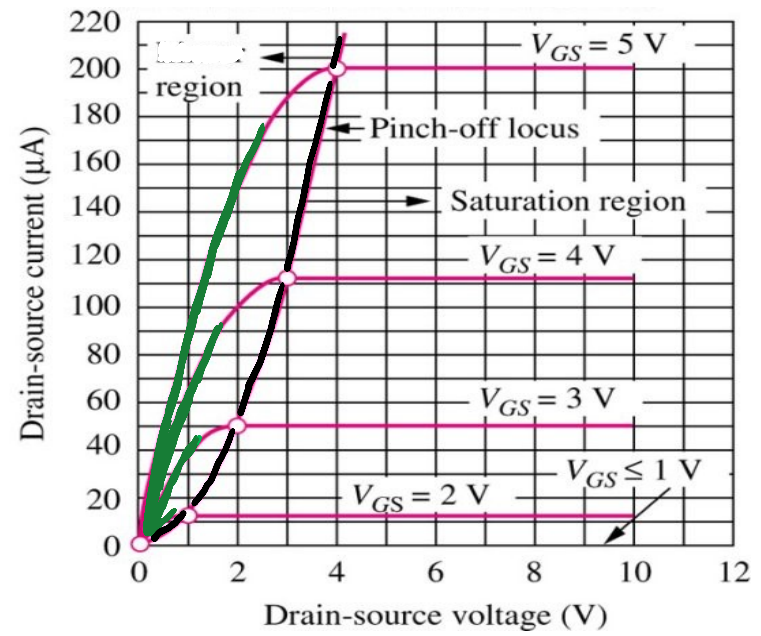


# NMOS Transistor: Region Summary



- If  $v_{DS} \ll V_{GS} - V_{TN}$  MOSFET is in **linear portion of the triode region**

Triode



Thank You!

